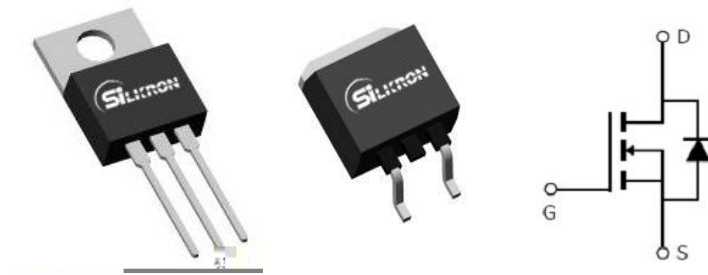


V_{DSS}	40V
$R_{DS(on)}$	2.4m Ω (typ.)
I_D	200A



Advanced MOSFET process technology
 Special designed for PWM, load switching and
 general purpose applications
 Ultra low on-resistance with low gate charge
 Fast switching and reverse body recovery
 175 operating temperature



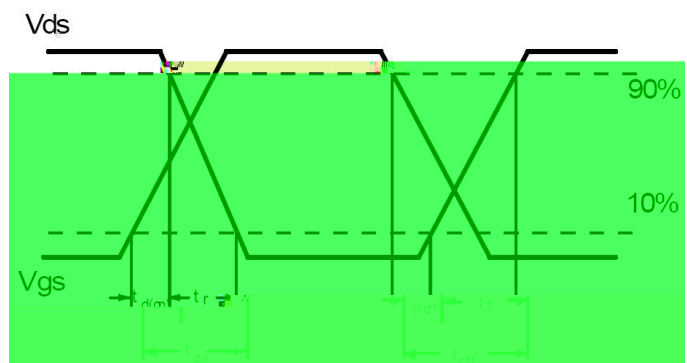
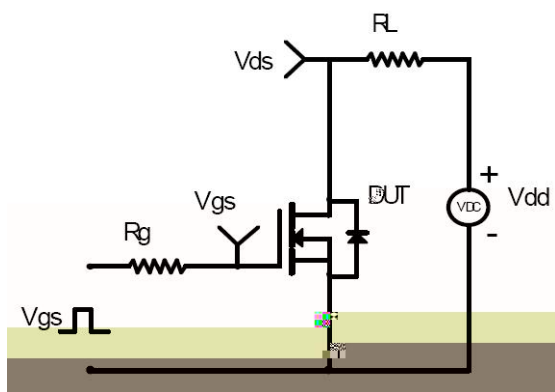
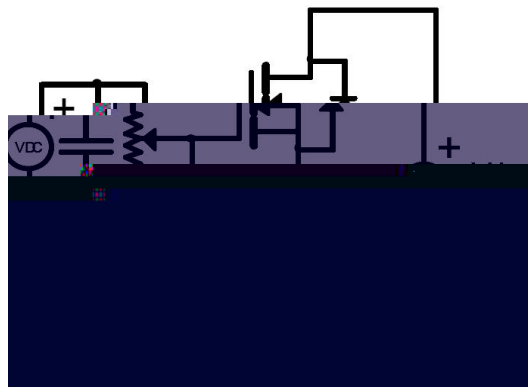
It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

$I_D @ TC = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	200	A
$I_D @ TC = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	135	
I_{DM}	Pulsed Drain Current	750	
$P_D @ TC = 25^\circ C$	Power Dissipation	220	W
	Linear Derating Factor	1.5	W/ $^\circ C$
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-to-Source Voltage	± 24	V
E_{AS}	Single Pulse Avalanche Energy @ $L=0.3mH$	912	mJ
I_{AS}	Avalanche Current @ $L=0.3mH$	78	A
$T_J \quad T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$



R _{θJC}	Junction-to-case	—	0.62	/W
R _{θJA}	Junction-to-ambient (t ≤ 10s)	—	60	/W
	Junction-to-Ambient (PCB mounted, steady-state)	—	40	/W

@T_A=25 unless other

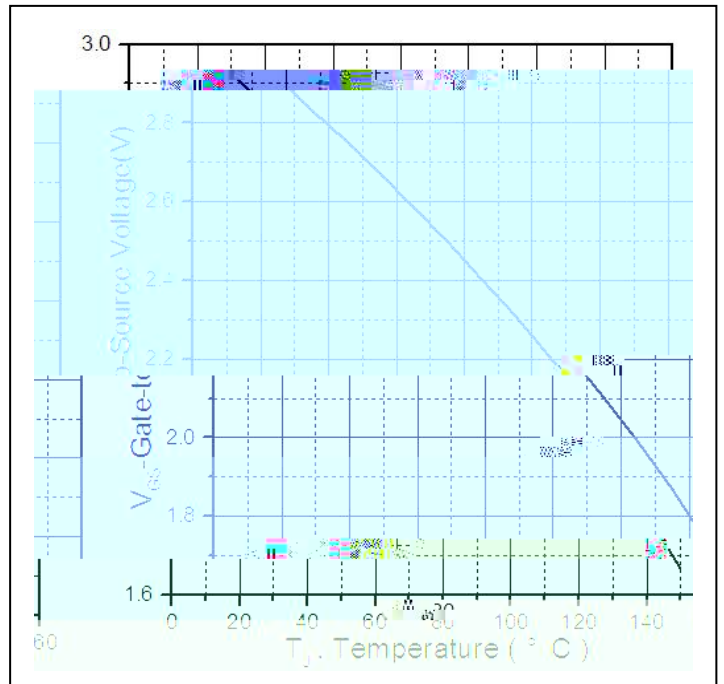
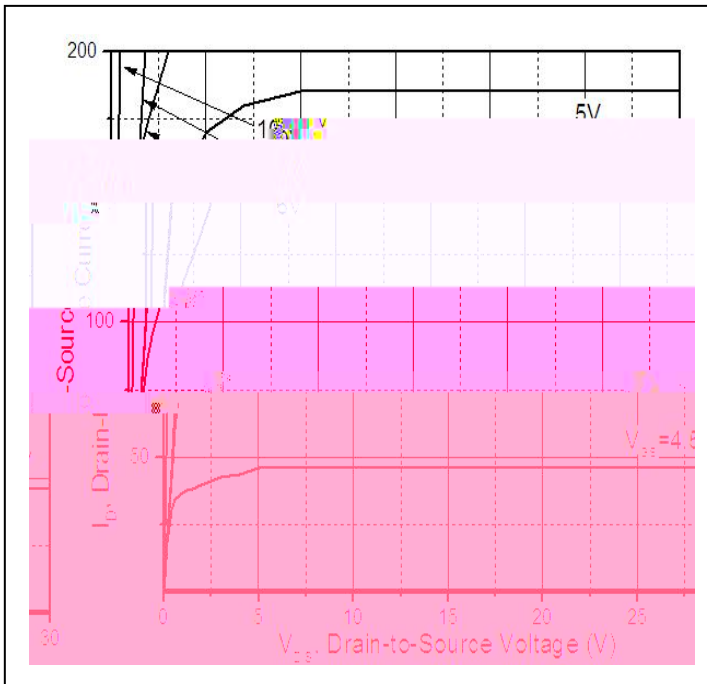


Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.

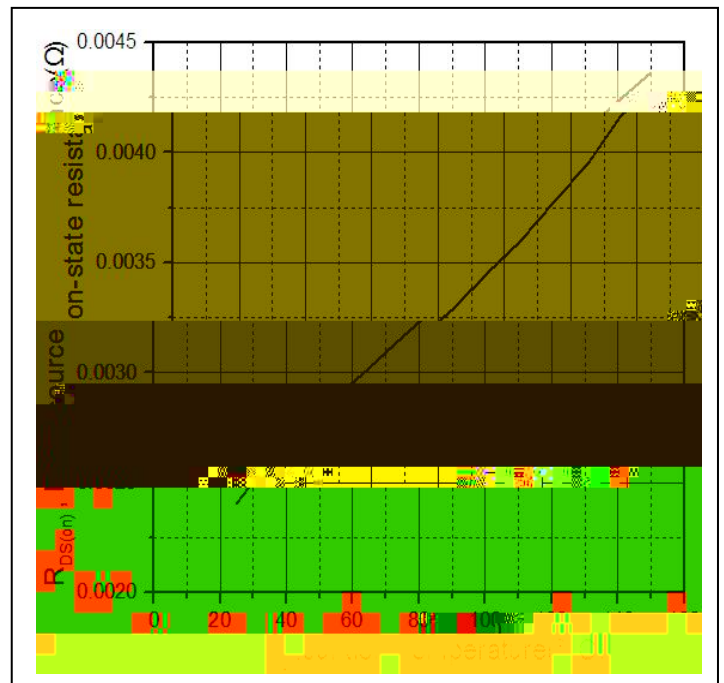
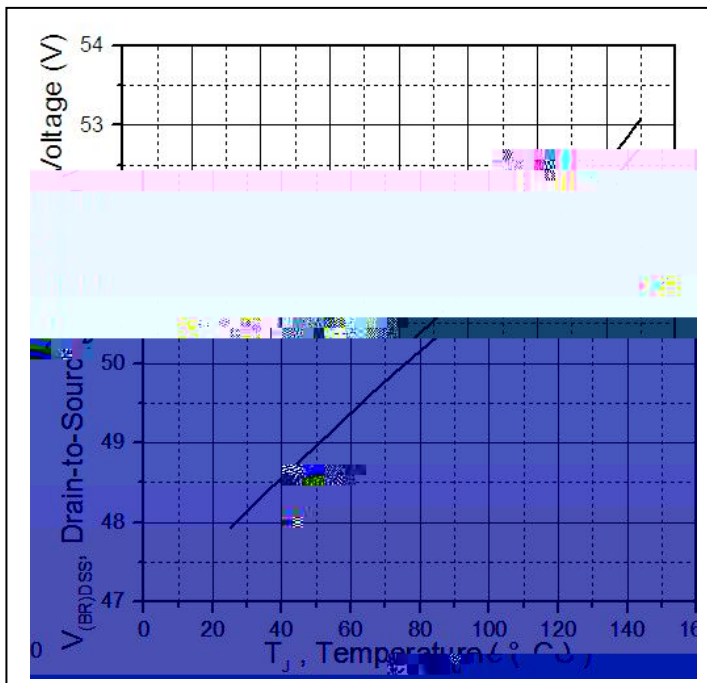
Repetitive rating; pulse width limited by max junction temperature.

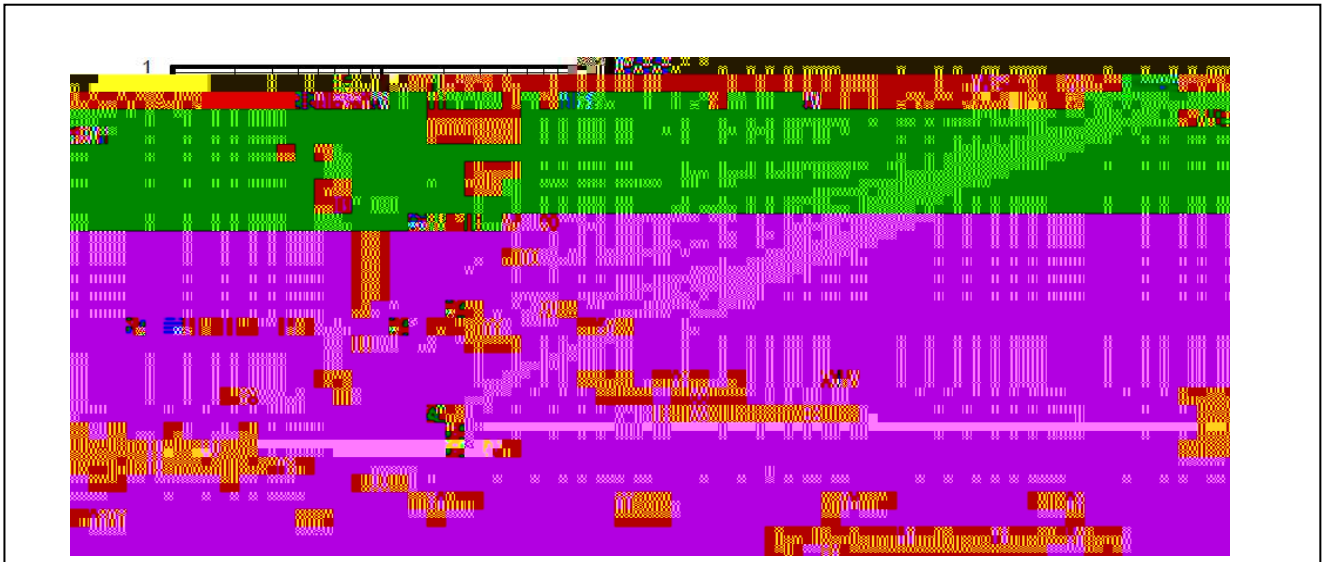
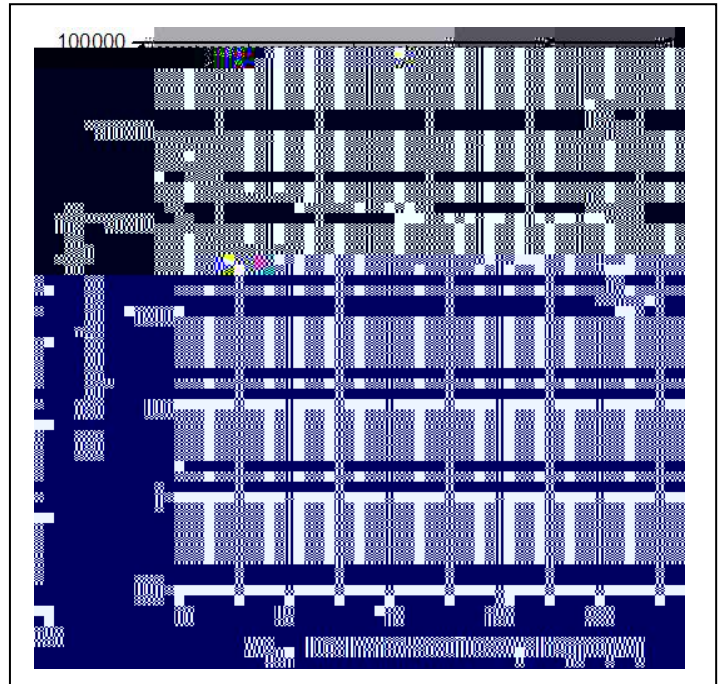
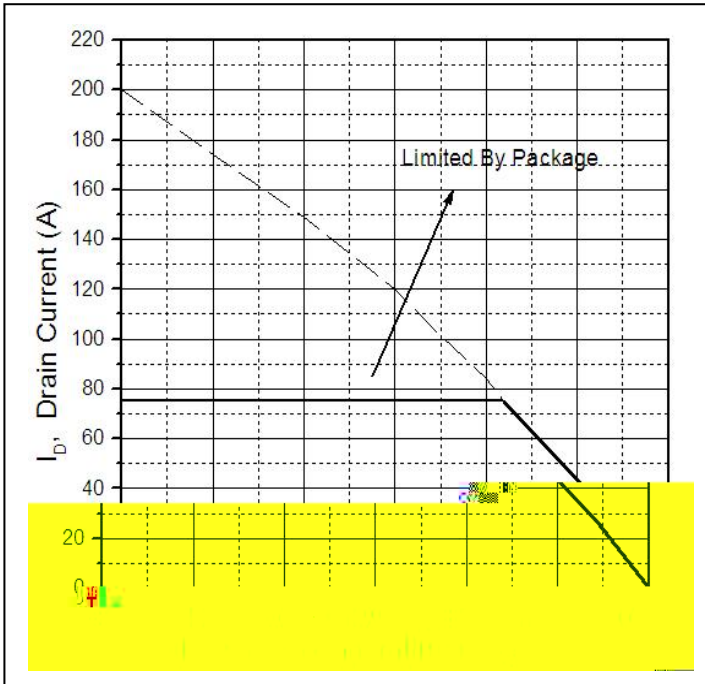
The power dissipation PD is based on max junction temperature, using junction-to-case thermal resistance.

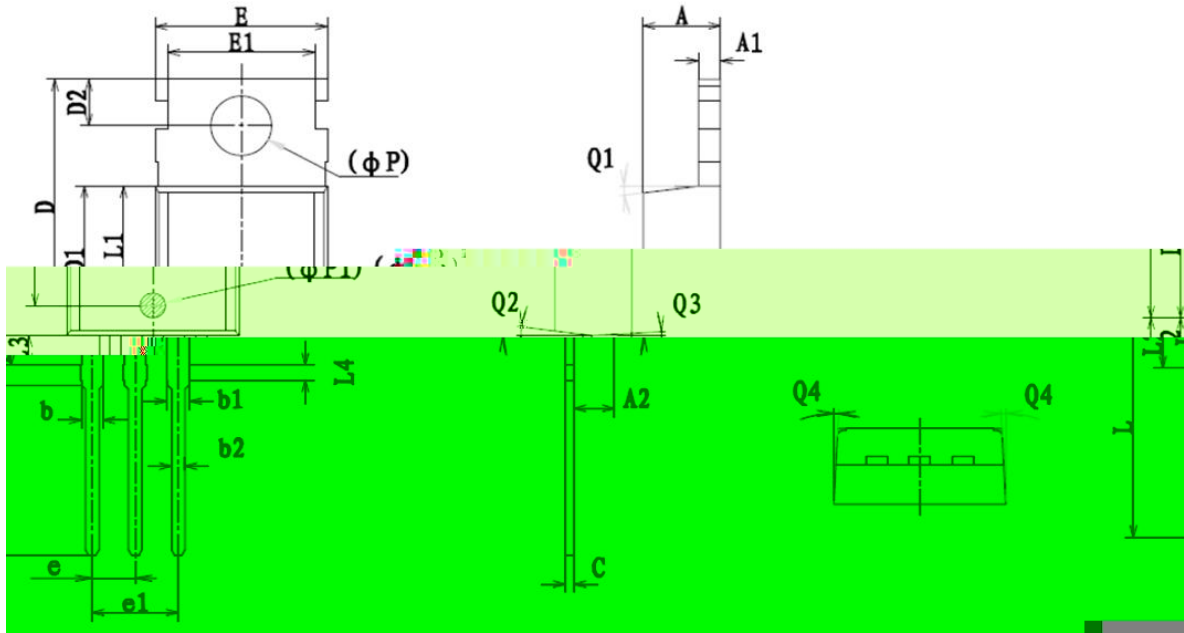
The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$



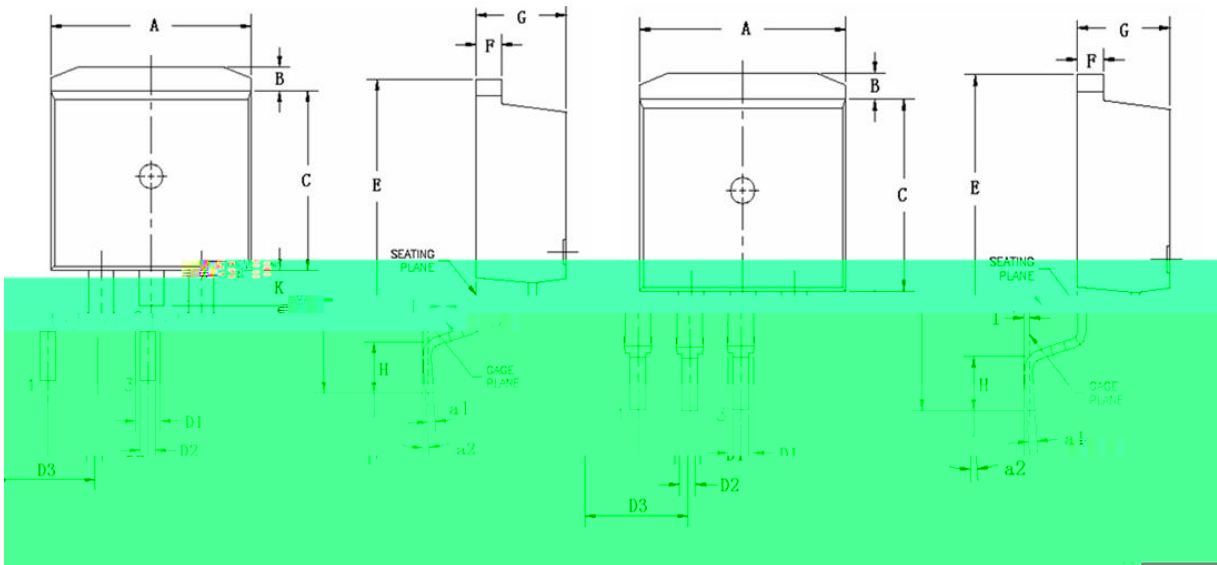
Gate to source cut-off Voltage







Symbol	Dimension In Millimeters	Dimension In Inches
E	100	3.937
$E1$	50	1.969
$D2$	100	3.937
D	100	3.937
$L1$	100	3.937
(ϕP)	50	1.969
A	150	5.906
$A1$	50	1.969
$Q1$	50	1.969
$Q2$	100	3.937
$Q3$	100	3.937
$L4$	100	3.937
$b1$	100	3.937
$b2$	100	3.937
$A2$	100	3.937
C	100	3.937
$Q4$	100	3.937
e	10	0.394
$e1$	10	0.394



Symbol	Dimension In Millimeters		Dimension In Inches	
	min	max	Min	Max
A	9.660	10.280	0.380	0.405
B	1.020	1.320	0.040	0.052
C	8.590	9.400	0.338	0.370
D1	1.180	1.480	0.046	0.058
D2	0.700	0.950	0.028	0.037
D3	5.080 (TYP)		0.200 (TYP)	
E	15.090	15.390	0.594	0.606
F	1.150	1.400	0.045	0.055
G	4.300	4.700	0.169	0.185



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